

18N50-MH Preliminary Power MOSFET

18A, 500V N-CHANNEL POWER MOSFET

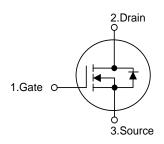
■ DESCRIPTION

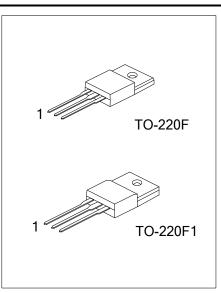
The UTC **18N50-MH** is a high voltage power MOSFET combines advanced trench MOSFET designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and high rugged avalanche characteristics. This power MOSFET is usually used in high speed switching applications of switching power supplies and adaptors.

■ FEATURES

- * $R_{DS(ON)} \le 0.3 \Omega$ @ $V_{GS}=10V$, $I_D=9.0A$
- * Fast switching capability
- * Avalanche energy tested
- * Improved dv/dt capability, high ruggedness

■ SYMBOL

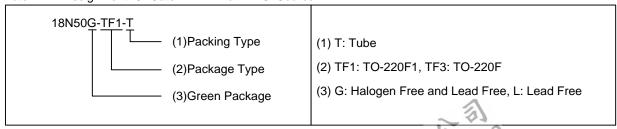




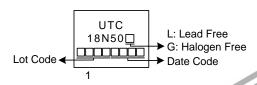
■ ORDERING INFORMATION

Ordering Number		Daakana	Pin Assignment			Dealing	
Lead Free	Halogen Free	Package	1	2	3	Packing	
18N50L-TF1-T	18N50G-TF1-T	TO-220F1	G	D	S	Tube	
18N50L-TF3-T	18N50G-TF3-T	TO-220F	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



■ MARKING



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■ ABSOLUTE MAXIMUM RATINGS (T_C=25°C, unless otherwise specified)

PARAMETER	SYMBOL	RATINGS	UNIT	
Drain-Source Voltage	V_{DSS}	500	V	
Gate-Source Voltage	V_{GSS}	V _{GSS} ±30		
Continuous Drain Current	I _D	18	Α	
Pulsed Drain Current (Note 2)	I _{DM}	36	Α	
Avalanche Energy Single Pulsed (No	te 3) E _{AS}	1380	mJ	
Peak Diode Recovery dv/dt (Note 4)	dv/dt	4.1	V/ns	
Power Dissipation	P _D	44	W	
Junction Temperature	TJ	+150	°C	
Storage Temperature	T _{STG}	-55 ~ + 150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 30mH, I_{AS} = 9.6A, V_{DD} = 100V, R_G = 25 Ω , Starting T_J = 25°C
- 4. $I_{SD} \le 9.0 A$, di/dt $\le 200 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25 ^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATING	UNIT	
Junction to Ambient	θ_{JA}	62.5	°C/W	
Junction to Case	θ_{JC}	2.84	°C/W	

■ **ELECTRICAL CHARACTERISTICS** (T_J=25°C, unless otherwise specified)

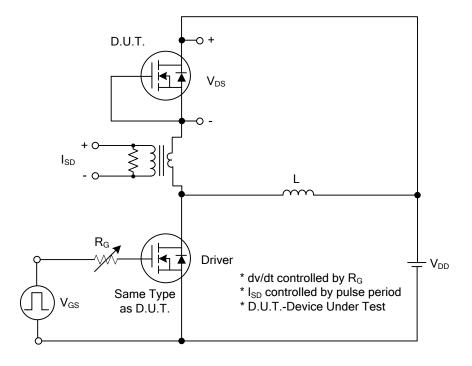
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PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage		BV _{DSS}	$V_{GS}=0V$, $I_D=250\mu A$	500			V	
Drain-Source Leakage Current		I _{DSS}	V_{DS} =500V, V_{GS} =0V			10	μA	
Gate- Source Leakage Current	Forward	I _{GSS}	$V_{GS}=30V$, $V_{DS}=0V$			100	nA	
	Reverse		V_{GS} =-30V, V_{DS} =0V			-100	nA	
ON CHARACTERISTICS								
Gate Threshold Voltage	Sate Threshold Voltage		$V_{DS}=V_{GS}$, $I_D=250\mu A$	2.0		4.0	V	
Static Drain-Source On-State Res	Static Drain-Source On-State Resistance		$V_{GS}=10V, I_{D}=9.0A$			0.3	Ω	
DYNAMIC CHARACTERISTICS								
Input Capacitance		C _{ISS}			2860		pF	
Output Capacitance	utput Capacitance		V _{DS} =25V, V _{GS} =0V, f=1.0MHz		305		pF	
Reverse Transfer Capacitance		C _{OSS}			40		pF	
SWITCHING CHARACTERISTICS								
Total Gate Charge (Note 1)	Gate Charge (Note 1)		V _{DS} =480V, V _{GS} =10V, I _D =18A		76		nC	
ate-Source Charge		Q_GS	$I_{G}=1$ mA (Note 1, 2)		13		nC	
Gate-Drain Charge	ate-Drain Charge		IG-TITIA (Note 1, 2)		28		nC	
urn-On Delay Time (Note 1)		t _{D(ON)}			38		ns	
Turn-On Rise Time			V _{DS} =100V, V _{GS} =10V, I _D =18A,		43		ns	
Turn-Off Delay Time			R _G =25Ω (Note 1, 2)		236		ns	
Turn-Off Fall Time		t _F		4			ns	
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS								
Maximum Body-Diode Continuous	Current	Is	10, V 0	(1)		18	Α	
Maximum Body-Diode Pulsed Current Drain-Source Diode Forward Voltage (Note 1)		I _{SM}	K PV CO			36	Α	
		V_{SD}	$I_S=18A$, $V_{GS}=0V$			1.4	V	
Reverse Recovery Time (Note 1)	verse Recovery Time (Note 1)		Is=18A , V _{GS} =0V		400		ns	
Reverse Recovery Charge		Qm	di/dt=100A/µs		12.5		μC	

Notes: 1. Pulse Test: Pulse width $\leq 300 \mu s$, Duty cycle $\leq 2\%$.

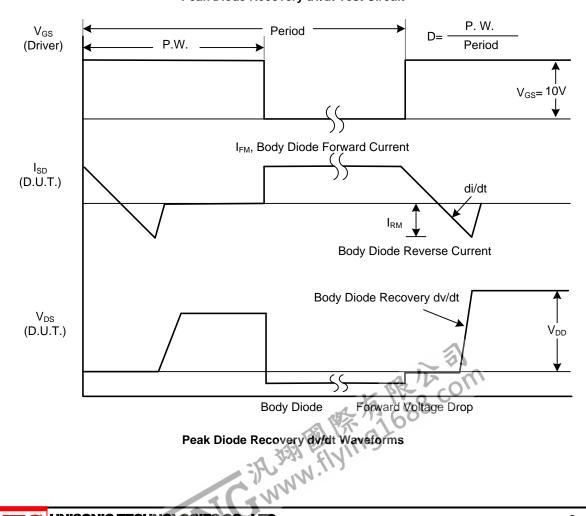
2. Essentially independent of operating temperature.



TEST CIRCUITS AND WAVEFORMS

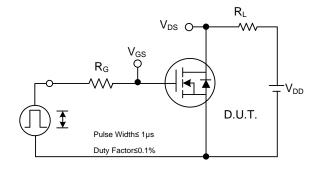


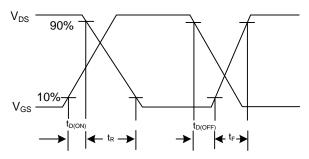
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

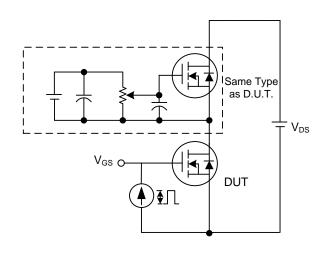
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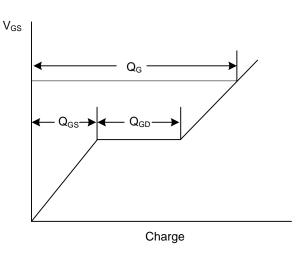




Switching Test Circuit

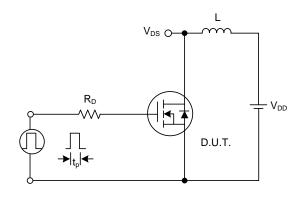
Switching Waveforms

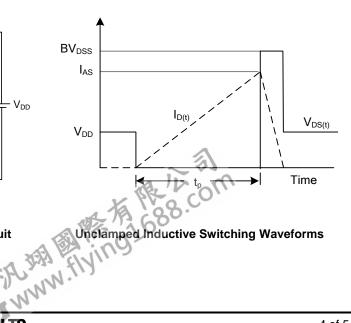




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

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